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FIG. 1

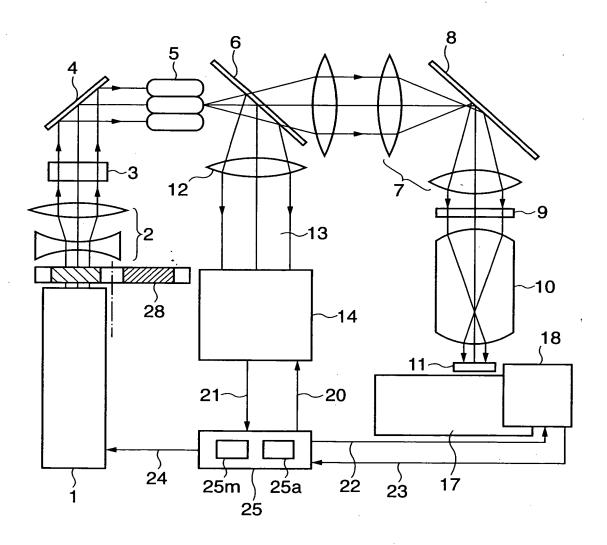
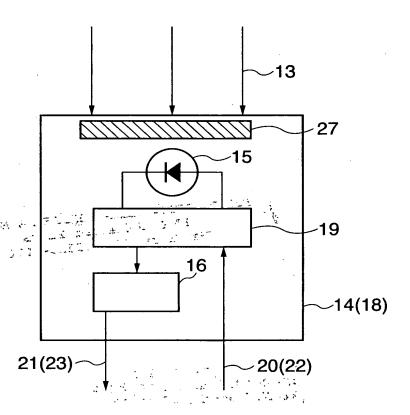
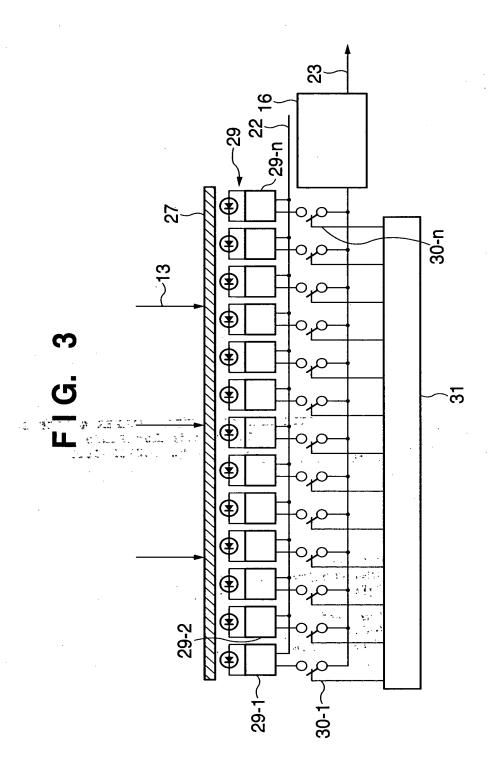


FIG. 2





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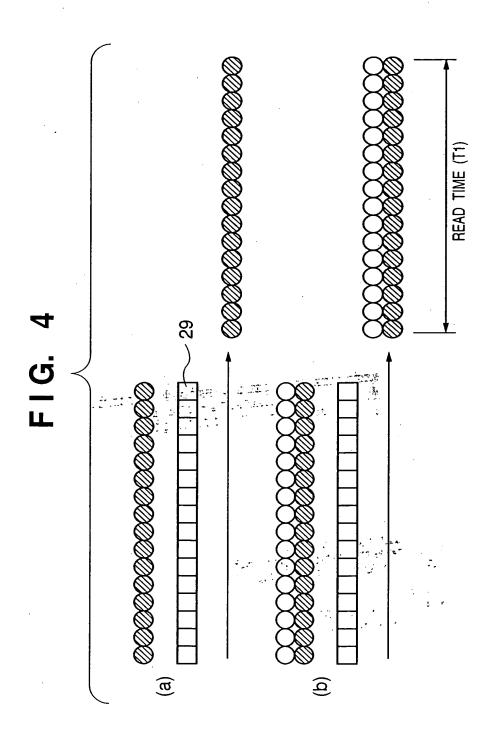


FIG. 5

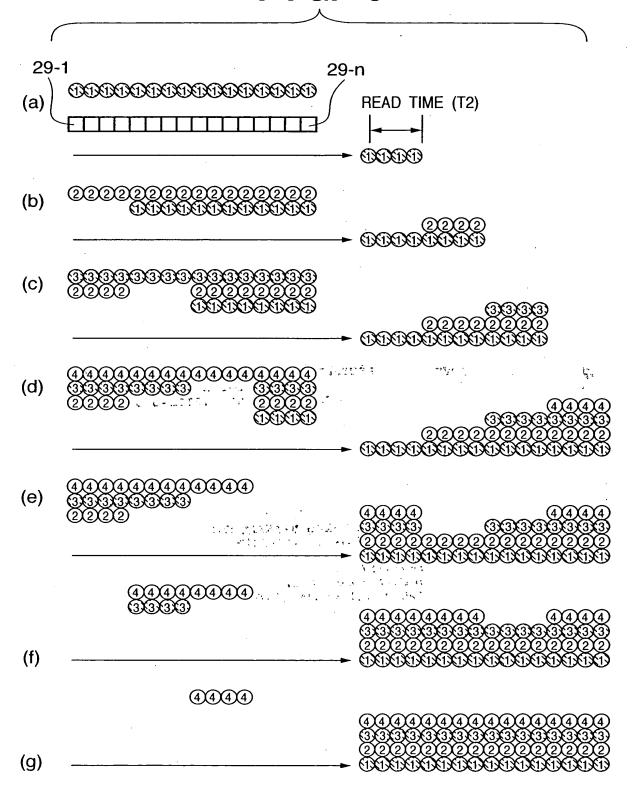
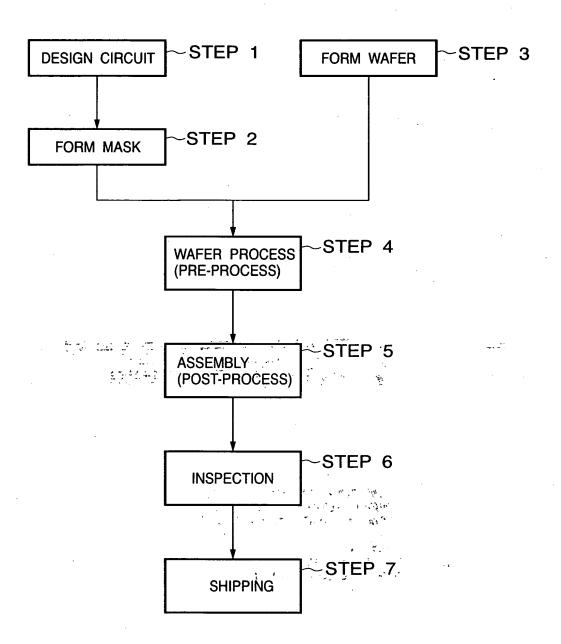


FIG. 6



SEMICONDUCTOR DEVICE MANUFACTURING FLOW

FIG. 7

